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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/605,650	CHANG, YEN-JEN	
Examiner	Art Unit	
Brian E. Miller	2627	

SEARCHED					
Class	Subclass	Date	Examiner		
720	692 694	10/12/2006	BEM		
720	698 688	10/12/2006	ВЕМ		
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Subclass		
	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Search (enclosed)	10/12/2006	ВЕМ	
PLUS Search	10/13/2006	ВЕМ	